TOSHIBA Digital Integrated Circuit Silicon Monolithic

# TC7SPN3125TU

#### Low Voltage/Low Power 1-Bit Dual Supply Bus Buffer

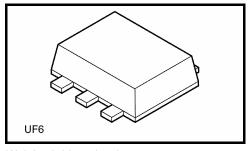
The TC7SPN3125 is a dual supply, advanced high-speed CMOS 1-bit dual supply voltage interface bus buffer fabricated with silicon gate CMOS technology.

It is also designed with over voltage tolerant inputs and outputs up to  $3.6\ V.$ 

Designed for use as an interface between a 1.2-V, 1.5-V, 1.8-V, or 2.5-V bus and a 1.8-V, 2.5-V or 3.6-V bus in mixed 1.2-V, 1.5-V, 1.8-V or 2.5-V/1.8-V, 2.5-V or 3.6-V supply systems.

The A-input interfaces with the 1.2-V, 1.5-V, 1.8-V or 2.5-V bus, the B-output with the 1.8-V, 2.5-V, 3.3-V bus.

The enable input (OE) can be used to disable the device so that the signal lines are effectively isolated.



Weight: 0.007 g (typ.)

All inputs are equipped with protection circuits against static discharge or transient excess voltage.

#### Features (Note)

- Level converter for interfacing 1.2-V to 1.8-V, 1.2-V to 2.5-V, 1.2-V to 3.3-V, 1.5-V to 2.5-V, 1.5-V to 3.3-V, 1.8-V to 2.5-V, 1.8-V to 3.3-V or 2.5 V to 3.3-V system.
- High-speed operation :  $t_{pd}$  = 13.7 ns (max) ( $V_{CCA}$  = 2.5 ± 0.2 V,  $V_{CCB}$  = 3.3 ± 0.3 V)

 $t_{pd}$  = 14.8 ns (max) (V<sub>CCA</sub> = 1.8 ± 0.15 V, V<sub>CCB</sub> = 3.3 ± 0.3 V)

 $t_{pd}$  = 16.0 ns (max) (V<sub>CCA</sub> = 1.5 ± 0.1 V, V<sub>CCB</sub> = 3.3 ± 0.3 V)

 $t_{pd}$  = 29 ns (max) (V<sub>CCA</sub> = 1.2 ± 0.1 V, V<sub>CCB</sub> = 3.3 ± 0.3 V)

 $t_{pd}$  = 18.5 ns (max) (V<sub>CCA</sub> = 1.8 ± 0.15 V, V<sub>CCB</sub> = 2.5 ± 0.2 V)

 $t_{pd} = 19.7 \text{ ns (max)} (V_{CCA} = 1.5 \pm 0.15 \text{ V}, V_{CCB} = 2.5 \pm 0.2 \text{ V})$ 

 $t_{pd} = 33 \text{ ns (max) (V}_{CCA} = 1.2 \pm 0.15 \text{ V}, V_{CCB} = 2.5 \pm 0.2 \text{ V})$ 

 $t_{pd} = 43 \text{ ns (max) (V}_{CCA} = 1.2 \pm 0.1 \text{ V}, V_{CCB} = 1.8 \pm 0.15 \text{ V})$ 

• Output current :  $I_{OH}/I_{OL} = \pm 3 \text{ mA (min) (V}_{CC} = 3.0 \text{ V)}$ 

 $I_{OH}/I_{OL} = \pm 2mA$  (min) ( $V_{CC} = 2.3$  V)

 $I_{OH}/I_{OL} = \pm 0.5 \text{ mA (min) (V}_{CC} = 1.65 \text{ V)}$ 

- Latch-up performance: -300 mA
- ESD performance: Machine model ≥ ±200 V

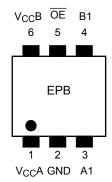
Human body model ≥ ±2000 V

- Ultra-small package: UF6
- Low current consumption: Using the new circuit significantly reduces current consumption when  $\overline{OE}$  = "H". Suitable for battery-driven applications such as PDAs and cellular phones.
- 3.6-V tolerant function and power-down protection provided on all inputs and outputs.

Note: Do not apply a signal to any bus pins when it is in the output mode. Damage may result.

## Pin Assignment (top view)





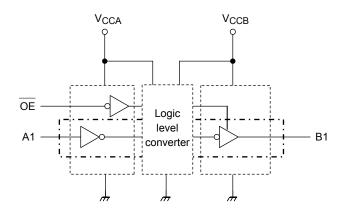
## **Truth Table**

Inputs		Output
ŌĒ	A1	B1
L	L	L
L	Н	Н
Н	Х	Z

X: Don't care

Z: High impedance

## **Block Diagram**



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#### **Absolute Maximum Ratings (Note 1)**

Characteristics		Symbol	Rating	Unit
Power supply voltage (	Note 2)	$V_{CCA}$	-0.5 to 4.6	V
Tower supply voltage (	Note 2)	V <sub>CCB</sub>	-0.5 to 4.6	
DC input voltage (A1, $\overline{OE}$ )		$V_{IN}$	-0.5 to 4.6	٧
DC output voltage		\/a=	-0.5 to 4.6 (Note 3)	) >
(B1)		V <sub>OUTB</sub>	-0.5 to V <sub>CCB</sub> + 0.5 (Note 4)	
Input diode current		l <sub>IK</sub>	-25	mA
Output diode current		lok	±50 (Note 5)	) mA
DC output current		I <sub>OUTB</sub>	±6	mA
DC Voo/ground current per sur	nly nin	I <sub>CCA</sub>	±25	mA
DC V <sub>CC</sub> /ground current per supply p		I <sub>CCB</sub>	±50	IIIA
Power dissipation		$P_{D}$	100	mW
Storage temperature		T <sub>stg</sub>	-65 to 150	°C

Note 1: Exceeding any of the absolute maximum ratings, even briefly, lead to deterioration in IC performance or even destruction.

Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings and the operating ranges.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Note 2: Don't supply a voltage to  $V_{CCB}$  pin when  $V_{CCA}$  is in the OFF state.

Note 3: Output in OFF state

Note 4: High or Low stats. IOUT absolute maximum rating must be observed.

Note 5:  $V_{OUT} < GND, V_{OUT} > V_{CC}$ 

#### **Operating Ranges (Note 1)**

Characteristics	Symbol	Rating	Unit
Power supply voltage	$V_{CCA}$	1.1 to 2.7	V
	V <sub>CCB</sub>	1.65 to 3.6	V
Input voltage (A1, $\overline{\sf OE}$ )	V <sub>IN</sub>	0 to 3.6	٧
Output voltage	V <sub>OUTB</sub>	0 to 3.6 (Note 2)	V
(B1)	VOOTB	0 to V <sub>CCB</sub> (Note 3)	V
Output current		±3 (Note 4)	
(B1)	loutb	±2 (Note 5)	mA
(61)		±0.5 (Note 6)	
Operating temperature	T <sub>opr</sub>	-40 to 85	°C
Input rise and fall time	dt/dv	0 to 10 (Note 7)	ns/V

Note 1: The operating ranges must be maintained to ensure the normal operation of the device.

Unused inputs must be tied to either VCC or GND.

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Note 2: Output in OFF state

Note 3: High or low state

Note 4:  $V_{CCB} = 3.0 \text{ to } 3.6 \text{ V}$ 

Note 5:  $V_{CCB} = 2.3 \text{ to } 2.7 \text{ V}$ 

Note 6:  $V_{CCB} = 1.65 \text{ to } 1.95 \text{ V}$ 

Note 7:  $V_{IN} = 0.8$  to 2.0 V,  $V_{CCA} = 2.5$  V,  $V_{CCB} = 3.0$  V



## **Electrical Characteristics**

## DC Characteristics (1.1 V $\leq$ V\_{CCA} $\leq$ 2.7 V , 1.65 V $\leq$ V\_{CCB} $\leq$ 3.6 V)

Ob and attacking	0	bol Test Condition				Ta = -40	to 85°C	1.1-24
Characteristics	Symbol	"	est Condition	V <sub>CCA</sub> (V)	V <sub>CCB</sub> (V)	Min	Max	Unit
				1.1≦V <sub>CCA</sub> <1.4	1.65 to 3.6	0.65× Vcc	_	٧
H-level input voltage	V <sub>IHA</sub>	V <sub>IN</sub>		1.4≦V <sub>CCA</sub> <1.65	1.65 to 3.6	0.65× Vcc	_	٧
		1.65≦V <sub>CCA</sub> <2.3	1.65 to 3.6	0.65× Vcc	_	V		
				2.3≦V <sub>CCA</sub> <2.7	1.65 to 3.6	1.6	_	V
				1.1≦V <sub>CCA</sub> <1.4	1.65 to 3.6	_	0.30× Vcc	٧
L-level input voltage	V <sub>ILA</sub>	V <sub>IN</sub>		1.4≦V <sub>CCA</sub> <1.65	1.65 to 3.6	_	0.30× Vcc	
		1.65≦V <sub>CCA</sub> <2.3	1.65 to 3.6	_	0.30× Vcc			
				2.3≦V <sub>CCA</sub> <2.7	1.65 to 3.6	_	0.7	
			I <sub>OHB</sub> = -100 μA	1.1 to 2.7	1.65 to 3.6	V <sub>CCB</sub> – 0.2	_	
H-level output voltage	V <sub>OHB</sub>	A1 = V <sub>IH</sub>	$I_{OHB} = -0.5 \text{ mA}$	1.1 to 2.7	1.65	1.25	_	V
H-level output voltage V <sub>O</sub>			I <sub>OHB</sub> = -2 mA	1.1 to 2.7	2.3	1.7	_	
			$I_{OHB} = -3 \text{ mA}$	1.1 to 2.7	3.0	2.2	_	
			$I_{OLB} = 100 \mu A$	1.1 to 2.7	1.65 to 3.6	_	0.2	
L-level output voltage	V <sub>OLB</sub>	A1 = V <sub>IL</sub>	$I_{OLB} = 0.5 \text{ mA}$	1.1 to 2.7	1.65	_	0.3	V
L lover output voltage	VOLB	/ (1 – V IL	I <sub>OLB</sub> = 2 mA	1.1 to 2.7	2.3	_	0.6	v
			I <sub>OLB</sub> = 3 mA	1.1 to 2.7	3.0	_	0.55	
3-state output OFF state current	I <sub>OZB</sub>	A1 = V <sub>IHA</sub> B1 = 0 to 3		1.1 to 2.7	1.65 to 3.6	_	±2.0	μΑ
Input leakage current	I <sub>IN</sub>	$V_{IN} = 0$ to	3.6 V	1.1 to 2.7	1.65 to 3.6	_	±1.0	μА
	I <sub>OFF1</sub>	V <sub>IN</sub> , B1 = 0	) to 3.6 V	0	0	_	2.0	
Power-off leakage current	I <sub>OFF2</sub>	OE = V <sub>CC</sub>	A	1.1 to 2.7	0	_	2.0	μА
	I <sub>OFF3</sub>	A1, B1 = 0	to 3.6 V	1.1 to 2.7	Open	_	2.0	
	I <sub>CCA</sub>	V <sub>IN</sub> = V <sub>CC</sub>	<sub>A</sub> or GND	1.1 to 2.7	1.65 to 3.6	_	2.0	
I <sub>CCB</sub> V <sub>IN</sub> = V <sub>CCA</sub> or GND	A or GND	1.1 to 2.7	1.65 to 3.6	_	2.0			
Quiescent supply current	ICCA	V <sub>CCA</sub> < V <sub>I</sub>	N ≦ 3.6 V	1.1 to 2.7	1.65 to 3.6	_	±2.0	μА
	ICCB	$V_{IN} = V_{CC}$ $V_{CCB} \le B1$		1.1 to 2.7	1.65 to 3.6	_	±2.0	

## AC Characteristics (Ta = -40 to $85^{\circ}$ C, Input: $t_r = t_f = 2.0$ ns)

## $\mbox{V}_{\mbox{CCA}} = 2.5 \pm 0.2 \mbox{ V}, \mbox{ } \mbox{V}_{\mbox{CCB}} = 3.3 \pm 0.3 \mbox{ V}$

Characteristics	Symbol	Test Condition	Min	Max	Unit
Propagation delay time	t <sub>pLH</sub>	Figure 1, Figure 2	1.0	13.7	
(A1 → B1)	t <sub>pHL</sub>				
3-state output enable time	t <sub>pZL</sub>	Figure 1, Figure 3	1.0	16.6	ns
( <del>OE</del> → B1)	t <sub>pZH</sub>				
3-state output disable time	t <sub>pLZ</sub>	Figure 1, Figure 3	1.0	7.2	
$(\overline{OE} \rightarrow B1)$	t <sub>pHZ</sub>	ga. o .,ga. o o		1.2	

## $V_{\text{CCA}} = 1.8 \pm 0.15 \text{ V}, V_{\text{CCB}} = 3.3 \pm 0.3 \text{ V}$

Characteristics	Symbol	Test Condition	Min	Max	Unit
Propagation delay time $(A1 \rightarrow B1)$	t <sub>pLH</sub>	Figure 1, Figure 2	1.0	14.8	
3-state output enable time $(\overline{OE} \rightarrow B1)$	t <sub>pZL</sub> t <sub>pZH</sub>	Figure 1, Figure 3	1.0	18.9	ns
3-state output disable time $(\overline{OE} \ \to B1)$	t <sub>pLZ</sub> t <sub>pHZ</sub>	Figure 1, Figure 3	1.0	8.7	

## $\mbox{Vcca} = 1.5 \pm 0.1 \mbox{ V, Vccb} = 3.3 \pm 0.3 \mbox{ V}$

Characteristics	Symbol	Test Condition	Min	Max	Unit
Propagation delay time $(A1 \rightarrow B1)$	t <sub>pLH</sub>	Figure 1, Figure 2	1.0	16.0	
3-state output enable time $(\overline{OE} \rightarrow B1)$	t <sub>pZL</sub> t <sub>pZH</sub>	Figure 1, Figure 3	1.0	22.8	ns
3-state output disable time $(\overline{OE} \rightarrow B1)$	t <sub>pLZ</sub> t <sub>pHZ</sub>	Figure 1, Figure 3	1.0	10.2	

## $V_{CCA} = 1.2 \pm 0.1$ V, $V_{CCB} = 3.3 \pm 0.3$ V

Characteristics	Symbol	Test Condition	Min	Max	Unit
Propagation delay time $(A1 \rightarrow B1)$	t <sub>pLH</sub> t <sub>pHL</sub>	Figure 1, Figure 2	1.0	29	
3-state output enable time $(\overline{OE}\ \to B1)$	t <sub>pZL</sub> t <sub>pZH</sub>	Figure 1, Figure 3	1.0	63	ns
3-state output disable time $(\overline{OE} \to B1)$	t <sub>pLZ</sub> t <sub>pHZ</sub>	Figure 1, Figure 3	1.0	23	

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## $V_{CCA} = 1.8 \pm 0.15$ V, $V_{CCB} = 2.5 \pm 0.2$ V

Characteristics	Symbol	Test Condition	Min	Max	Unit
Propagation delay time	t <sub>pLH</sub>	Figure 1, Figure 2	1.0	18.5	
(A1 → B1)	t <sub>pHL</sub>				
3-state output enable time	t <sub>pZL</sub>	Figure 1, Figure 3	1.0	23.6	ns
$(\overline{OE} \rightarrow B1)$	t <sub>pZH</sub>	rigure 1, rigure 3	1.0	23.0	110
3-state output disable time	t <sub>pLZ</sub>	Figure 1, Figure 3	4.0		
$(\overline{OE} \to B1)$	t <sub>pHZ</sub>	i iguie i, i iguie 3	1.0	6.9	

## $\mbox{Vcca} = 1.5 \pm 0.1 \mbox{ V, Vccb} = 2.5 \pm 0.2 \mbox{ V}$

Characteristics	Symbol	Test Condition	Min	Max	Unit
Propagation delay time $(A1 \rightarrow B1)$	t <sub>pLH</sub> t <sub>pHL</sub>	Figure 1, Figure 2	1.0	19.7	
3-state output enable time $(\ \overline{OE} \ \to B1)$	t <sub>pZL</sub> t <sub>pZH</sub>	Figure 1, Figure 3	1.0	26.6	ns
3-state output disable time $(\overline{OE} \to B1)$	t <sub>pLZ</sub> t <sub>pHZ</sub>	Figure 1, Figure 3	1.0	8.3	

## $\mbox{Vcca} = 1.2 \pm 0.1 \mbox{ V, Vccb} = 2.5 \pm 0.2 \mbox{ V}$

Characteristics	Symbol	Test Condition	Min	Max	Unit
Propagation delay time $(A1 \rightarrow B1)$	t <sub>pLH</sub> t <sub>pHL</sub>	Figure 1, Figure 2	1.0	33	
3-state output enable time $(\overline{OE}\toB1)$	t <sub>pZL</sub> t <sub>pZH</sub>	Figure 1, Figure 3	1.0	66	ns
3-state output disable time ( OE → B1)	t <sub>pLZ</sub> t <sub>pHZ</sub>	Figure 1, Figure 3	1.0	20	

## $V_{CCA} = 1.2 \pm 0.1$ V, $V_{CCB} = 1.8 \pm 0.15$ V

Characteristics	Symbol	Test Condition	Min	Max	Unit
Propagation delay time $(A1 \rightarrow B1)$	t <sub>pLH</sub> t <sub>pHL</sub>	Figure 1, Figure 2	1.0	43	
3-state output enable time $(\overline{\sf OE} \ \to \sf B1)$	t <sub>pZL</sub> t <sub>pZH</sub>	Figure 1, Figure 3	1.0	78	ns
3-state output disable time $(\overline{OE} \rightarrow B1)$	t <sub>pLZ</sub> t <sub>pHZ</sub>	Figure 1, Figure 3	1.0	20	

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## **Capacitive Characteristics (Ta=25°C)**

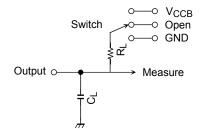
Characteristics		Symbol	Test Circuit			Тур.	Unit
Citalacteristics		Symbol	rest officult	V <sub>CCA</sub> (V)	V <sub>CCB</sub> (V)		
Input capacitance		C <sub>IN</sub>	ŌĒ, A1	2.5	3.3	7	pF
Output capacitance		C <sub>OUT</sub>	B1	2.5	3.3	8	pF
Power dissipation capacitance	(Note)	C <sub>PDA</sub>	/OE="L"	2.5	3.3	3	
			/OE="H"	2.5	3.3	0	- pF
		(Note) C <sub>PDB</sub>	/OE="L"	2.5	3.3	13	
			/OE="H"	2.5	3.3	0	

Note: C<sub>PD</sub> is defined as the value of the internal equivalent capacitance which is calculated from the operating current consumption without load.

Average operating current can be obtained by the equation:

 $I_{CC (opr)} = C_{PD} \cdot V_{CC} \cdot f_{IN} + I_{CC}/2 (per bit)$ 

#### **AC Test Circuit**



Parameter	Switch	
t <sub>pLH</sub> , t <sub>pHL</sub>	Open	
t <sub>pLZ</sub> , t <sub>pZL</sub>	V <sub>CCB</sub>	
t <sub>pHZ</sub> , t <sub>pZH</sub>	GND	

Complete	Vccв			
Symbol	$\begin{array}{c} 3.3 \pm 0.3 \; \text{V} \\ 2.5 \pm 0.2 \; \text{V} \end{array}$	1.8 ± 0.15 V		
$R_L$	1 kΩ	1 kΩ		
$C_L$	30 pF	30 pF		

Figure 1

#### **AC Waveform**

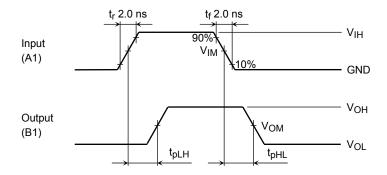


Figure 2 t<sub>pLH</sub>, t<sub>pHL</sub>

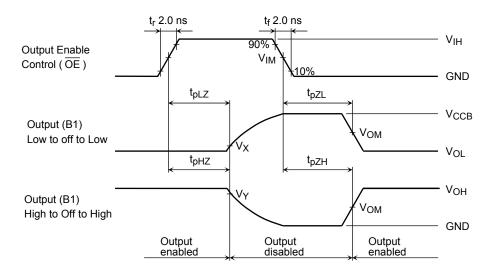


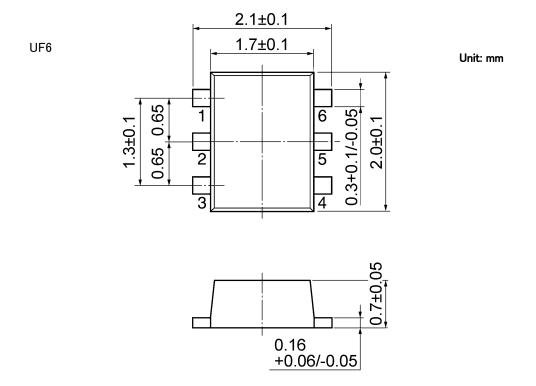
Figure 3  $t_{pLZ}$ ,  $t_{pHZ}$ ,  $t_{pZL}$ ,  $t_{pZH}$ 

		V <sub>CCA</sub> , V <sub>CCB</sub>				
Symbol		3.3 ± 0.3 V	$2.5\pm0.2~\textrm{V}$	1.5 ± 0.1 V		
		3.3 ± 0.3 V	$1.8\pm0.15~\textrm{V}$	$1.2\pm0.1~\textrm{V}$		
Input	V <sub>IH</sub>	-	V <sub>CCA</sub>	V <sub>CCA</sub>		
	V <sub>IM</sub>	1	V <sub>CCA</sub> /2	V <sub>CCA</sub> /2		
Output	V <sub>OM</sub>	V <sub>OH</sub> /2	V <sub>OH</sub> /2	-		
	VX	V <sub>OL</sub> + 0.3 V	V <sub>OH</sub> + 0.15 V	-		
	VY	V <sub>OH</sub> – 0.3 V	V <sub>OH</sub> – 0.15 V	-		

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2007-10-19

## **Package Dimensions**



weight: 0.007 g (typ.)

#### **RESTRICTIONS ON PRODUCT USE**

20070701-EN GENERAL

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